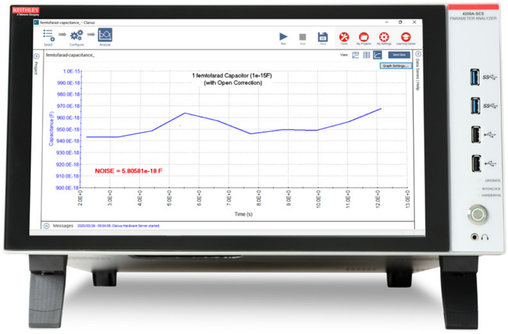
Mastering Electrical Characterization Seminar

This session, led by a Keithley Applications Engineer, will explore the challenges and best practices in low current and low voltage measurements using the Keithley 4200A-SCS Parameter Analyzer.

Gain practical insights into optimizing their setups for device characterization, enhancing measurement accuracy, and overcoming noise, leakage, and connection limitations common in lab and wafer-level testing. Whether you're testing nanoscale devices, advanced semiconductors, or novel materials, this seminar will give you the knowledge to get the most out of your instrumentation.

AGENDA

- DC I-V Characterization Fundamentals: Understanding SMU operation
- Voltage Measurement Challenges and Solutions: Noise floor and source loading issues
- Low Current Measurement Techniques: Common error sources, including triboelectric effects, contamination, leakage
- Best Practices for Cabling, Cables, and Probing
- Applications in Semiconductor & Research Labs
- Q&A and Discussion



UNIVERSITY OF TORONTO

Date: Wednesday, May 28

Time: 12 PM - 5 PM

University of Toronto
6 King's College Road
Bratt Building
Room: PT473

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